

U.S. Department of Commerce, Patent and Trademark Office				Docket No.: 3816.06-C1				
				Serial No.: 10/829,641				
O I P LIST OF RELEVANT ART CITED BY APPLICANT <i>APR 21 2004</i> (Use several sheets if necessary)				Applicant: Ranaan ZEHAVI et al.				
				Filing Date: April 22, 2004				
				Group: 2818				
U.S. PATENT DOCUMENTS								
*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate	
MM	AA	5,492,229	02/20/96	Tanaka et al.	211	41.18	_____	
MM	AB	5,516,283	05/14/96	Schrems	432	241	_____	
MM	AC	5,534,074	07/09/96	Koons	118	728	_____	
MM	AD	5,586,880	12/24/96	Ohsawa	432	241	_____	
MM	AE	5,595,604	01/21/97	Kobayashi et al.	118	715	_____	
MM	AF	5,752,609	05/19/98	Kato et al.	211	41.18	_____	
MM	AH	5,779,797	07/14/98	Kitano et al.	118	500	_____	
MM	AI	5,858,103	01/12/99	Nakajima et al.	118	728	_____	
MM	AJ	5,931,666	08/03/99	Hengest	432	258	_____	
FOREIGN PATENT DOCUMENTS (Translation)								
		Document Number	Date	Country	Class	Subclass	Yes	No
MM	AL	WO 00/21119	04/13/00	PCT	_____	_____	X	
MM	AM	EP 0 884 769 A 1	12/16/98	Europe	_____	_____	X	
	AN							
	AO							
	AP							
OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.)								
	AR	anonymous, "Epi-II advanced Wafer," MEMC Applications Note, AE-003, March 2000, pp. 1-4						
	AS	anonymous, "Thin epi layers shown to improve gate oxide integrity performance," MEMC, date unknown, 1.p						
	AT							
Examiner	<i>Y. H. Dey</i>		Date Considered	<i>9-29-04</i>				
*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with your communication to applicant.								

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<i>MJ</i>	AA	6,065,615	05/23/00	Uchiyama et al.	211	41.18	—	
<i>MJ</i>	AB	6,171,982	01/09/01	Sato	438	795	—	
<i>MJ</i>	AC	6,180,497	01/30/01	Sato et al.	438	458	—	
<i>MJ</i>	AD	6,284,997	09/04/01	Zehavi et al.	219	121.46	—	
<i>MJ</i>	AE	6,450,346	09/17/02	Boyle et al.	219	41.18	—	
<i>MJ</i>	AF	6,727,191	04/27/04	Zehavi et al.	438	795	12/23/98	
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	AH							
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